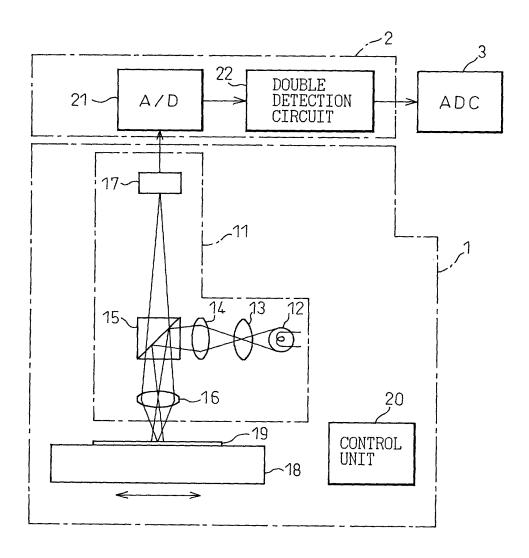
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Fig.1



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Fig.2A

DIE-DIE COMPARISON

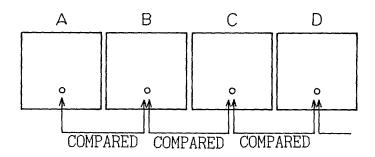
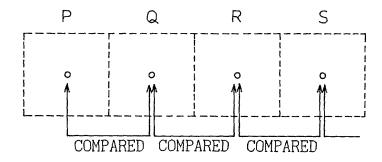


Fig.2B

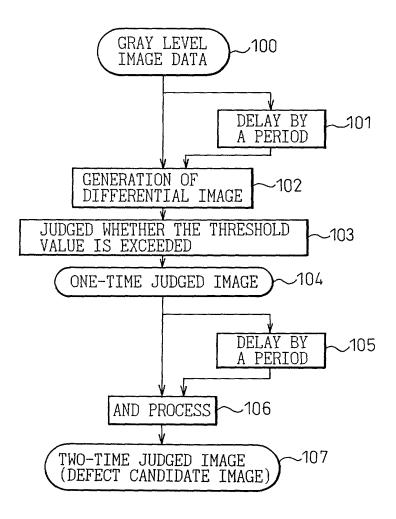
CELL-CELL COMPARISON



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Fig. 3



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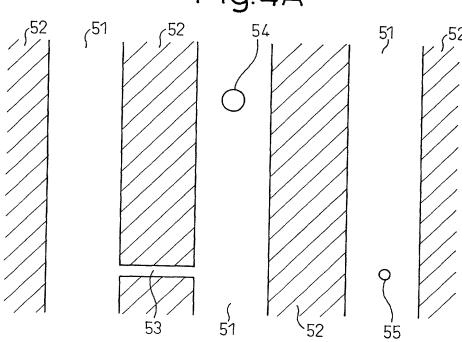
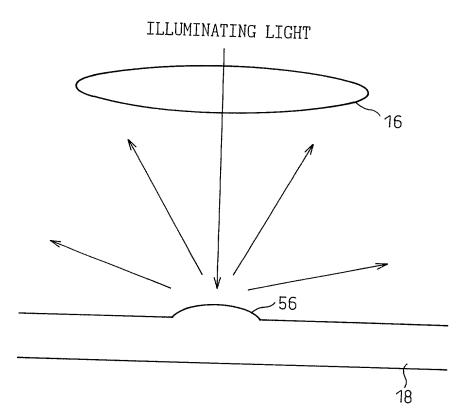


Fig.4B

·	54,4							5				51A			/52A				
30	30	120	200	200	120	30	30	120	200	200	120	30	30	120	200	200	120	30	30
30	30	120	200	200	120	30	30	120	200	200	120	30	30	120	200	200	120	30	30
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30	30	120	200	200	120	30	30	120	200	200	120	30	30	120/	200	200	120	30	30
30	30	120	200	200	120	3þ	30	120	200	200	120	30	30	/1	200		-	30	30
53A										<u>-</u>	55A								

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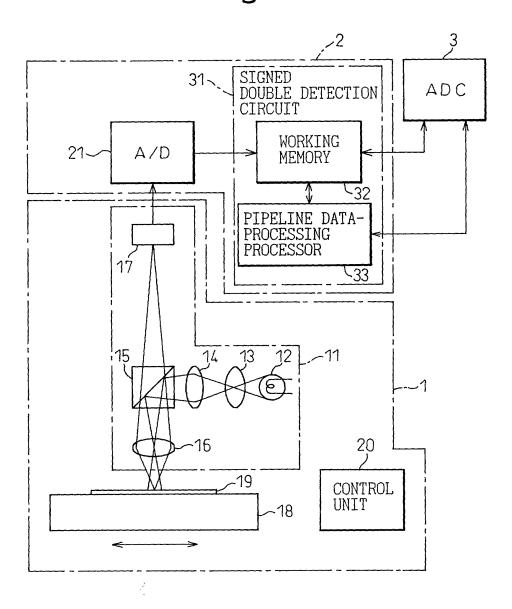
Fig.5



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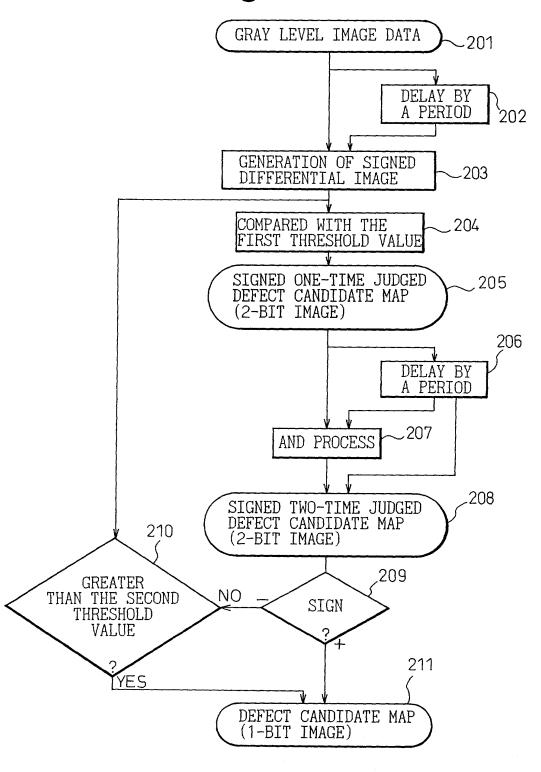
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Fig.6



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Fig.7





GRAY LEVEL IMAGE

Fig.8B

IMAGE DELAYED BY A PERIOD

Fig.8C

SIGNED ONE-TIME JUDGED DEFECT CANDIDATE MAP

Fig.8D

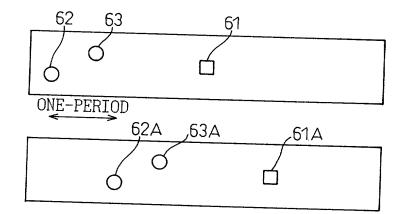
ONE-PERIOD DELAYED ONE-TIME JUDGED MAP

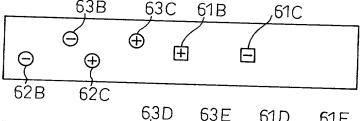
Fig.8E

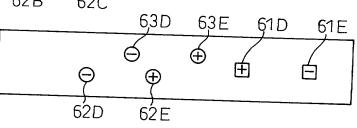
SIGNED TWO-TIME JUDGED MAP

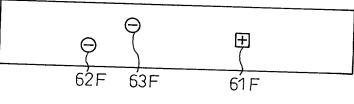
Fig.8F

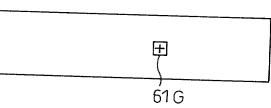
DEFECT MAP







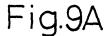




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GRAY LEVEL IMAGE

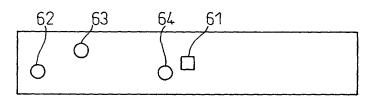


Fig.9B

IMAGE DELAYED BY A PERIOD

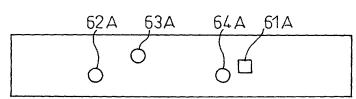


Fig.9C

SIGNED ONE-TIME JUDGED DEFECT CANDIDATE MAP

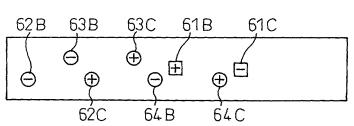


Fig.9D

ONE-PERIOD DELAYED ONE-TIME JUDGED MAP

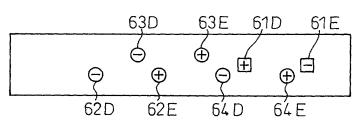


Fig.9E

SIGNED TWO-TIME JUDGED MAP

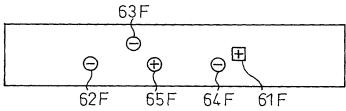
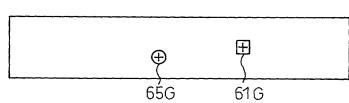


Fig.9F

DEFECT MAP



Attorney: Docket No.: D Bruce Prout 47779/DBP/A400

Inventor(s): Masayuki Kuwabara Title: PATTERN INSPECTION METHOD AND INSPECTION APPARATUS

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Fig.10A

SIGNED TWO-TIME JUDGED MAP

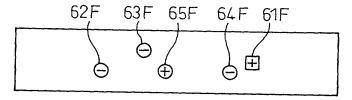
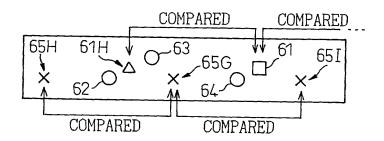


Fig.10B

GRAY LEVEL IMAGE



D Bruce Prout Attorney: Docket No.: 47779/DBP/A400 Inventor(s): Masayuki Kuwabara Title: PATTERN INSPECTION METHOD AND

INSPECTION APPARATUS

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Fig.11

